8NM70-FD Preliminary Power MOSFET

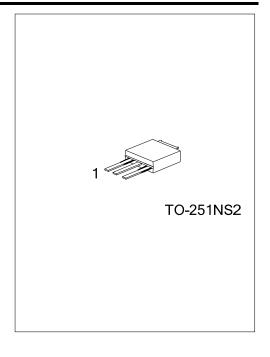
8A, 700V N-CHANNEL SUPER-JUNCTION MOSFET

■ DESCRIPTION

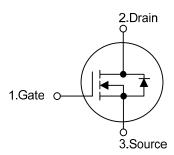
The **UTC 8NM70-FD** is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at DC-DC, AC-DC converters for power applications.

■ FEATURES

- * $R_{DS(ON)} < 0.9 \Omega$ @ $V_{GS} = 10V$, $I_{D} = 4.0A$
- * Fast Switching Capability
- * Avalanche Energy Tested
- * Improved dv/dt Capability, High Ruggedness



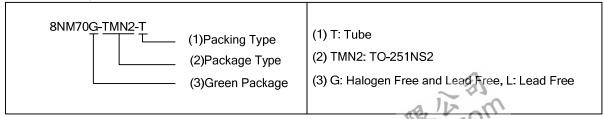
■ SYMBOL



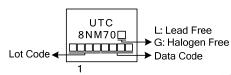
■ ORDERING INFORMATION

Ordering Number		Doolsono	Pin Assignment			Daakina	
Lead Free	Halogen Free	Package	1	2	3	Packing	
8NM70L-TMN2-T	8NM70G-TMN2-T	TO-251NS2	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING



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■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	700	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Drain Current	Continuous	I_{D}	8.0	Α	
	Pulsed (Note 2)	I_{DM}	32	Α	
Avalanche Energy	valanche Energy Single Pulsed (Note 3)		175	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	12	V/ns	
Power Dissipation		P_D	70	W	
Junction Temperature		T_J	+150	°C	
Storage Temperature		T_{STG}	-55 ~ + 150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=66mH, I_{AS} =2.3A, V_{DD} =50V, R_{G} =25 Ω , Starting T_{J} = 25°C
- 4. $I_{SD} \le 8A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	110	°C/W	
Junction to Case	θ_{JC}	1.92	°C/W	

■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

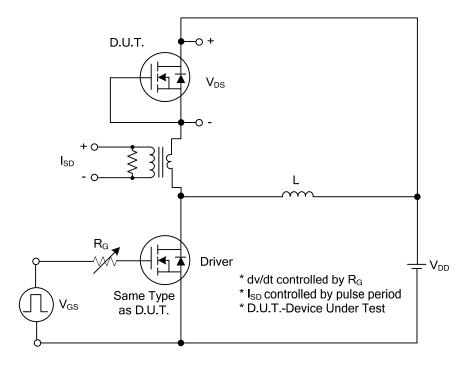
DADAMETED		CVMDOL	TECT CONDITIONS	NAINI	TVD	MANY	LINIT
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	ITP	MAX	UNIT
OFF CHARACTERISTICS			h				·
Drain-Source Breakdown Voltage		BV _{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	700			V
Drain-Source Leakage Current		I _{DSS}	$V_{DS} = 700V, V_{GS} = 0V$			10	μΑ
Gate- Source Leakage Current	Forward	I _{GSS}	$V_{GS} = 30V$, $V_{DS} = 0V$			100	nA
	Reverse	1688	$V_{GS} = -30V, V_{DS} = 0V$			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.5	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	$V_{GS} = 10V, I_D = 4.0A$			0.9	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C _{ISS}			430		pF
Output Capacitance		Coss	V _{GS} =0V, V _{DS} =25V, f=1.0 MHz		260		pF
Reverse Transfer Capacitance		C _{RSS}]		38		pF
SWITCHING CHARACTERISTICS							
Total Gate Charge (Note 1)		Q_G	V _{DS} =50V, V _{GS} =10V, I _D =1.3A,		52		nC
Gate to Source Charge		Q_GS	I _G =100μA (Note 1, 2)		4		nC
Gate to Drain Charge		Q_GD	IG-TOOPA (Note 1, 2)		14		nC
Turn-ON Delay Time (Note 1)		t _{D(ON)}	V_{DD} =30V, V_{GS} =10V, I_{D} =0.5A, R_{G} =25 Ω (Note 1, 2)		44		ns
Rise Time		t _R			81		ns
Turn-OFF Delay Time		t _{D(OFF)}			179		ns
Fall-Time		t _F			63		ns
SOURCE- DRAIN DIODE RATING	S AND CHA	RACTERIST	rics				
Maximum Body-Diode Continuous Current		Is	A 112 C			8	Α
Maximum Body-Diode Pulsed Current		I _{SM}	LIKE CO'	*		32	Α
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I _S =8.0A, V _{GS} =0V			1.4	V
Body Diode Reverse Recovery Time (Note 1)		t _{rr}	I _S =8.0A, V _{GS} =0V,		136		ns
Body Diode Reverse Recovery Charge		Q _{rr}	dl _F /dt=100A/µs		0.73		μC

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%.

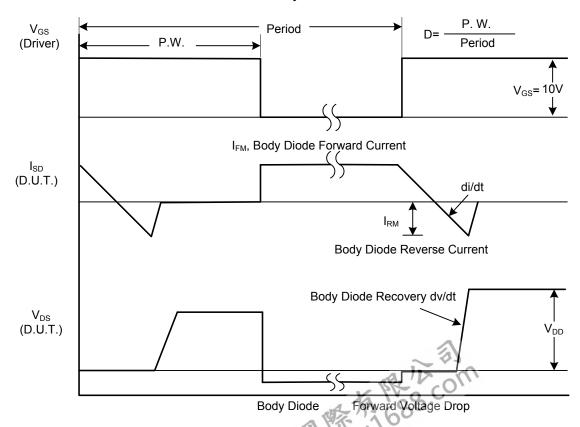
2. Essentially independent of operating temperature.



TEST CIRCUITS AND WAVEFORMS

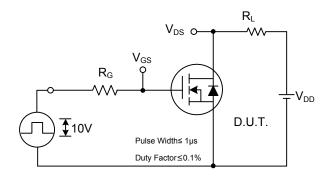


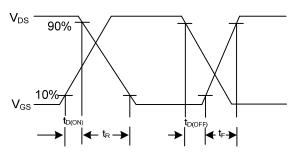
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dw/dt Waveforms

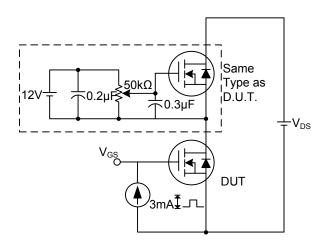
TEST CIRCUITS AND WAVEFORMS (Cont.)

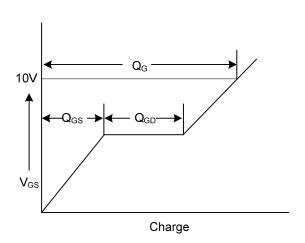




Switching Test Circuit

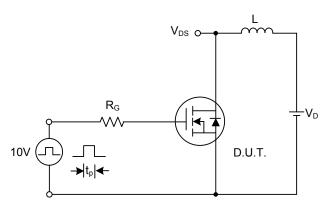
Switching Waveforms

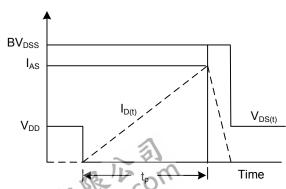




Gate Charge Test Circuit

Gate Charge Waveform





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